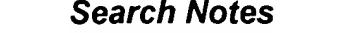


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/862,772	KIM ET AL.
	Examiner	Art Unit
	HUY T. NGUYEN	2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner